

Oostergracht 40 3763 LZ Soest The Netherlands T +31(0)35 - 603 81 81 F +31(0)35 - 603 81 80 M info@dis-sensors.nl W www.dis-sensors.com

EC - Declaration of conformity (

Manufacturer: DIS Sensors by

Device: Inclination & acceleration sensors, QG40N Tilt switch SIL1 PLc series

Declaration: Manufacturer declares, on his sole responsibility, conformity of this device

according to all CE regulations / directives / standards specified below

EMC directive: Electromagnetic Compatibility directive 2014/30/EU

EMC standards:

• EN 61000-6-2 (2005) + AC(2005)

Generic EMC immunity standard for industrial environments

• EN 61000-6-3 (2007) + A1 (2011) + AC(2012)

Generic EMC emission standard for light industrial environments

EN 12895 (2000) + (2015)

EMC immunity & emission standard for Industrial trucks

EN 61326-1 (2013)

EMC immunity & emission standard for electronic equipment. for measurement, control and laboratory use

• EN 50121-4 (2006) + (2015)

EMC immunity & emission standard for Railway applications

• EN 50121-3-2 (2016)

EMC immunity & emission standard for Railway applications

• IEC 61326-3-1 (2008)

EMC immunity standard for Electrical equipment for safety-related systems for General industrial applications, measurements, control and laboratory use.

RoHS & RoHS II: RoHS European Directive 2002/95/EC & RoHS II European Directive 2011/65/EU

REACH: REACH European Regulation 1907/2006/EC





Oostergracht 40 3763 LZ Soest The Netherlands T +31(0)35 - 603 81 81 F +31(0)35 - 603 81 80 M info@dis-sensors.nl W www.dis-sensors.com

Functional Safety:

According to European Directive 2006/42/EC of the European Parliament and of the Council on Machinery

According to European Standard EN ISO 13849

- Performance Level PLc
- Hardware Architecture CAT.2
- System Type B
- Proof test interval 20 years
- The firmware of this device is developed according to EN ISO 13849 and meets the SRESW requirements for both 'PL a to d' and 'PL c or d'

According to European Standard IEC 62061

- Safety Integrity Level SIL CL 1
- Hardware Architecture HFT = 0
- System Type B
- Proof test interval 20 years

MTTFd: 433 year
DCavg: 73%
CCF: 65pt
SFF: 93%
PFHd: 1,5E-07 /h

ISO: Quality system EN ISO 9001

Date: This device is CE-marked November 2017

M. van Andel, Product Manager

